3	Search Notes			

,	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/045,306	CHEN ET AL.
	Examiner	Art Unit
	Christopher L. Chin	1641

	SEARCHED		
Class	Subclass	Date	Examiner
Updated	Search	5/2/2005	CC

INTERFERENCE SEARCHED		
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SEARCH (INCLUDING SEAF		GY)
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